

Title (en)  
GLASS INSPECTION SYSTEMS AND METHODS FOR USING SAME

Title (de)  
GLASPRÜFUNGSSYSTEM UND VERFAHREN ZU SEINER VERWENDUNG

Title (fr)  
SYSTEMES D'INSPECTION DE VERRE ET PROCEDES D'UTILISATION

Publication  
**EP 1866625 A4 20101229 (EN)**

Application  
**EP 06749504 A 20060406**

Priority

- US 2006013012 W 20060406
- US 66917105 P 20050406

Abstract (en)  
[origin: WO2006108137A2] Several different inspection systems and methods are described herein that identify defects (e.g., inclusions, onclusions, scratches, stains, blisters, cords or other imperfections associated with surface discontinuities or material non-homogeneities) on or within a glass sheet.

IPC 8 full level  
**G01N 21/00** (2006.01); **G01N 21/89** (2006.01); **G01N 21/90** (2006.01)

CPC (source: EP KR)  
**G01N 21/21** (2013.01 - KR); **G01N 21/45** (2013.01 - KR); **G01N 21/896** (2013.01 - EP KR); **G01N 21/958** (2013.01 - KR); **G01N 21/21** (2013.01 - EP); **G01N 21/45** (2013.01 - EP); **G01N 21/958** (2013.01 - EP); **G01N 2021/1774** (2013.01 - EP KR); **G01N 2021/8965** (2013.01 - EP KR); **G01N 2201/0612** (2013.01 - EP KR); **G01N 2201/0635** (2013.01 - EP KR); **G01N 2201/0638** (2013.01 - EP KR)

Citation (search report)

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Designated contracting state (EPC)  
DE FR

DOCDB simple family (publication)  
**WO 2006108137 A2 20061012; WO 2006108137 A3 20061116**; CN 101175986 A 20080507; CN 101175986 B 20101013; EP 1866625 A2 20071219; EP 1866625 A4 20101229; JP 2008536127 A 20080904; KR 20070121820 A 20071227; TW 200706859 A 20070216; TW I360652 B 20120321

DOCDB simple family (application)  
**US 2006013012 W 20060406**; CN 200680016105 A 20060406; EP 06749504 A 20060406; JP 2008505569 A 20060406; KR 20077025683 A 20071105; TW 95112334 A 20060406